


IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

<p>In re application of:</p> <p>MARAKHTANOV et al</p> <p>Serial No.: 10/808,795</p> <p>Filed: March 24, 2004</p> <p>Title: PLASMA PROCESSING SYSTEM CONTROL</p>		<p>Group Art Unit: 2821</p> <p>Examiner: UNASSIGEND</p> <p>Docket: P1220/LMRX-P030</p> <p>Confirmation No.: 6020</p>
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INFORMATION DISCLOSURE STATEMENT

US PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number	Publication Date	Name of Patentee or Applicant	Reference to Related Case
		US 5933314	1999-08-03	Lambson et al.	

FOREIGN PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number	Publication Date	Applicant	Reference to Related Case	T

OTHER DOCUMENTS

Examiner Initials	Cite No.		T
		Kawamura et al., "Ion energy distributions in RF sheaths: review, analysis and simulation", 1999, Plasma Sources Science Technology 8, R45-R64.	
WJ		Lieberman et al., "Principles of Plasma Discharges and Materials Processing", 1994, New York, John Wiley and Sons, Inc..	

Examiner Signature	David W	Date Considered	9/3/05
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